

Notice of References Cited	Application/Control No. 09/876,977	Applicant(s)/Patent Under Reexamination WENZEL ET AL.	
	Examiner Antonio A Caschera	Art Unit 2676	Page 1 of 1

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	B	US-6,222,940	04-2001	Wenzel et al.	382/217
	C	US-6,529,193	03-2003	Herken et al.	345/426
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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